Notice of References Cited Application/Control No. 10/750,028 Examiner Kyung Hye Shin Applicant(s)/Patent Under Reexamination MEYERS ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,437,803 B1	08-2002	Panasyuk et al.	715/733
*	В	US-6,587,125 B1	07-2003	Paroz, Dani	715/740
*	С	US-6,662,207 B2	12-2003	Kawamura et al.	709/202
*	D	US-6,983,328 B2	01-2006	Beged-Dov et al.	709/230
*	Е	US-7,171,444 B2	01-2007	Deshpande, Sachin G.	709/203
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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